Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,828	BEENAU ET AL.
Examiner	Art Unit
Daniel I. Walsh	2876

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
	Subclass	Subclass Date			

	CH NOTES EARCH STRATEGY)
	DATE	EXMR
reviewed 10710317	7/12/2006	DW